

Total No. of Questions : 8]

SEAT No. :

P4836

[Total No. of Pages : 3

[5060]-743

M.E. (E & TC) (VLSI & Embedded Systems)

FAULT TOLERANT SYSTEMS

(2013 Pattern) (Credit System) (Semester - III)

Time : 3 Hours]

[Max. Marks : 50

Instructions to the candidates:-

- 1) *Neat diagrams must be drawn wherever necessary.*
- 2) *Assume suitable data, if necessary.*
- 3) *Solve any five questions.*

Q1) a) Construct a primitive cube table for the following equation. **[3]**

$$F = \overline{X_1} \overline{X_2} + X_1 \overline{X_2} + \overline{X_1} X_2 X_3$$

b) What do you mean by Static and Dynamic Hazards? Explain? **[4]**

c) Define unknown logic value and construct truth tables of 3 - valued logic for OR & AND gate. **[3]**

Q2) a) Write short note on Delay Modeling with timing diagrams for different delay models. **[4]**

b) Define and explain Event driven simulation in detail. **[3]**

c) Construct a binary decision diagram for a given function. **[3]**

$$F = A \overline{B} C + \overline{A} C + BC$$

P.T.O.

Q3) a) For the circuit of figure. 1

[5]

- i) Find the set of all tests that detects the fault $c s-a-1$.
- ii) Find the set of all tests that detects the fault $a s-a-0$.
- iii) Find the set of all tests that detects the multiple faults $\{c s-a-1, a s-a-0\}$.

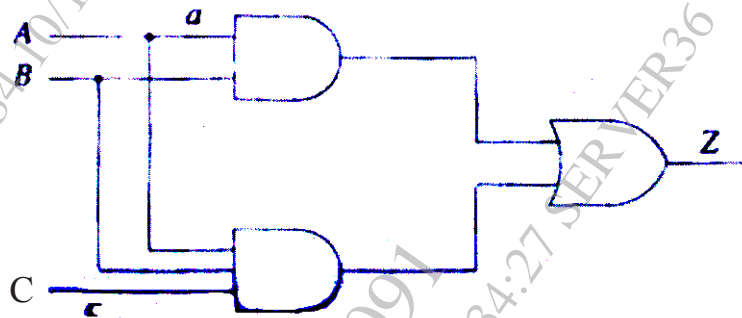


Figure .1

b) Explain in brief

[5]

- i) Fault dominance
- ii) Equivalent fault collapsing
- iii) Dominance fault collapsing

Q4) a) Explain in detail different fault models. Give their advantages and disadvantages. **[6]**

b) Explain any two techniques of DFT to increase controllability and predictability? **[4]**

- Q5)** a) Explain in brief parity check function with self checking 3-bit parity checker and general self-checking parity checker. [5]
- b) Give classification of different compression techniques. Explain parity check compression. [5]
- Q6)** a) Explain signature analyzer in compression techniques. Also give one Example. [5]
- b) Write a brief note explaining the working of self checking Berger code. [5]
- Q7)** a) Write short note on built in self test. [5]
- b) Explain in detail: PLA testing. [5]
- Q8)** a) What is error masking? Give the techniques to measure masking techniques to measure masking characteristics in compression techniques? [5]
- b) Explain in detail logical fault model. [5]

